TOSHIBA PHOTOCOUPLER IRED & PHOTO-IC

TLP104

IPM (Intelligent Power Module)
Industrial Inverter
Operate at high ambient temperatures up to 125°C

The Toshiba TLP104 consists of an infrared LED and integrated high gain, high-speed photodetectors. The TLP104 is housed in the SO6 package. The output stage is an open collector type.

The photodetector has an internal Faraday shield that provides a guaranteed common-mode transient immunity of ± 15 kV/ μ s. TLP104 guarantees minimum and maximum of propagation delay time, switching speed dispersion, and high common mode transient immunity. Therefore TLP104 is suitable for isolation interface between IPM (Intelligent Power Module) in motor control application.

- Inverter logic type (Open collector output)
- Package type: SO6
- Guaranteed performance over temperature: -40 to 125°C
- Power supply voltage: -0.5 to 30 V
- Threshold Input Current: IFHL = 5.0 mA (max)
- Propagation delay time (tpHL/tpLH): tpHL = 400ns (max)

 $t_{pLH} = 550 ns (max)$

- Switching Time Dispersion(|tpHL-tpLH|): 400ns (max)
- Common mode transient immunity : ±15kV/μs (min)
- Isolation voltage

3750Vrms (min)

- UL-recognized: UL 1577, File No.E67349
- cUL-recognized : CSA Component Acceptance Service No.5A

File No.E67349

- VDE-approved : EN 60747-5-5, EN 62368-1 (Note 1)
- CQC-approved: GB4943.1, GB8898 Thailand Factory

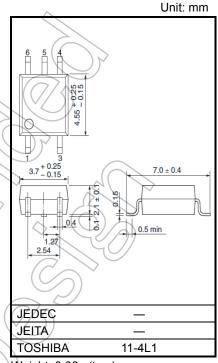


仅适用干海拔 2000m 以下地区安全使用

Note 1: When a VDE approved type is needed, please designate the **Option(V4)**.

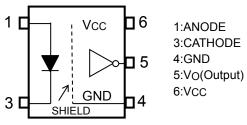
Truth Table

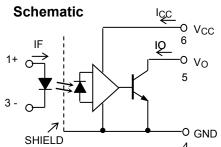
Input	LED	Output
Н	ON	L
L	OFF	Н



Weight: 0.08 g(typ.)

Pin Configuration (Top View)





Construction Mechanical Ratings

	•
Creepage distance	5.0 mm (min)
Clearance distance	5.0 mm (min)
Insulation thickness	0.4 mm (min)

Start of commercial production 2009-10

Absolute Maximum Ratings (Ta = 25°C)

	Characteristic		Symbol	Rating	Unit
	Forward Current		lF	25	mA
	Forward Current Derating (Ta ≥ 110°C)		ΔI _F /°C	-0.67	mA/°C
	Pulse Forward Current	(Note 1)	lFP	50 <	mA
LED	Pulse Forward Current Derating (Ta ≥ 110°C)		ΔI _{FP} /°C	-1.34	mA/°C
	Reverse Voltage		V _R	5	((v))
	Input Power Dissipation		PD	40	mW
	Input power Dissipation Derating (Ta ≥ 110°C)		ΔP _D /°C <	-1.0	mW/°C
	Output Current (Ta ≤ 125°C)		l _O	8	mA
jo.	Output Voltage		VO	-0.5 to 30	V
Detector	Supply Voltage		Vcc	-0.5 to 30	V
ă	Output Power Dissipation		Po	80	mW 🔍
	Output Power Dissipation Derating (Ta ≥ 110°C)		ΔP _O /°C	-2.0	mW/°C
Oper	ating Temperature Range		Topr	-40 to 125	(°C)
Stora	ge Temperature Range		T _{stg}	-55 to 125	~ e-/
Lead	Soldering Temperature (10 s)		T _{sol}	260	°C \
Isola	tion Voltage (AC,60 s, R.H.≤ 60 %,Ta=25°C)	(Note 2)	BV _S	3750	V _{rms}

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Note 1: Pulse width \leq 10 μ s, duty=10 %.

Note 2: This device is regarded as a two terminal device: pins 1 and 3 are shorted together, as are pins 4, 5 and 6.

Recommended Operating Conditions

Characteristic	Symbol	Min	Тур.	Max	Unit
Input Current , High Level	IFHL	7.5	ı	15	mA
Input Voltage , Low Level	V _{FLH}	0	ı	0.8	V
Supply Voltage*	VCC	4.5	ı	30	V
Operating Temperature	Topr	-40	-	125	°C

^{*} This item denotes operating range, not meaning of recommended operating conditions.

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Electrical Characteristics

(Unless otherwise specified, Ta = -40 to 125°C, VCC =4.5 to 30V)

	Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
	Forward voltage	VF	_	I _F = 10 mA, Ta = 25 °C	1.45	1.61	1.85	V
	Forward voltage temperature coefficient	ΔV _F / ΔTa	-	I _F = 10 mA		-1.8	-	mV /°C
LED	Reverse current	IR	_	V _R = 5 V, Ta = 25 °C	+(13	10	μΑ
	Capacitance between terminals	Ст		V = 0 V, f = 1 MHz		60		pF
	High level output current	Іон	1	V _F = 0.8 V, V _O < V _{CC}	(-)	_	50	μА
_	Low level output voltage	VoL	2	I _F = 10 mA, I _O = 2.4 mA)	0.2	0.6	V
Detector	Low level supply current	ICCL	3	I _F = 10 mA)	_	1.3	mA
De	High level supply current	Іссн	4	I _F = 0 mA	_	<i>←</i>	1.3	mA
	Output current	lo	_	I _F = 10 mA, V _O = 0.6 V	4.0	74/	\searrow	mA
Inpu	ut current logic LOW output	I _{FHL}	_	I _O = 0.75mA, V _O < 0.8 V	- /	1,0	> 5	mA
Inpu	ut voltage logic HIGH output	V _{FLH}	_	I _O = 0.75mA, V _O > 2.0 V	0.8) —	V

^{*}All typical values are at Ta = 25 $^{\circ}$ C, V_{CC} = 5 V unless otherwise specified

Isolation Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Conditions	Min	Тур.	Max	Unit
Capacitance input to output	Cs	Vs = 0 V, f = 1 MHz	-	0.8	1	pF
Isolation resistance	Rs	R.H. ≤ 60 %, V _S = 500 V	10 ¹²	10 ¹⁴	_	Ω
Isolation voltage	BVS	AC,60 s	3750	_	_	V _{rms}

Switching Characteristics (Unless otherwise specified, Ta = -40 to 125°C, Vcc=15V)

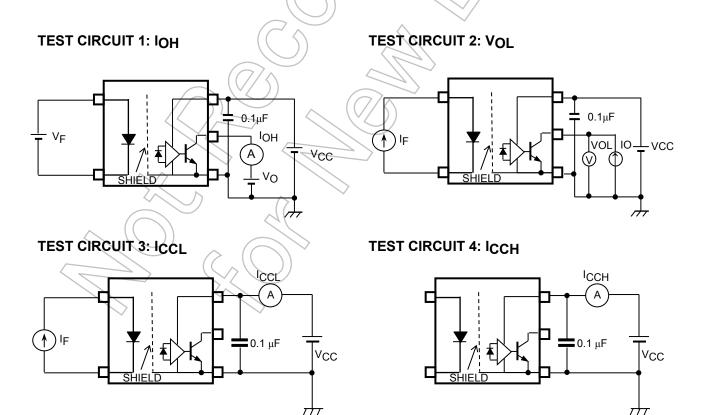
Characteristic	Symbol	Test Circuit	Test Condition		Min	Тур.	Max	Unit			
Dranagation delay time (II))	4						C _L =100 pF	30	150	400	
Propagation delay time (H→L)	tpHL			C _L =10 pF	_	90	_				
Dranagation delay time (L. 11)	•	I _F = 10 mA,		C _L =100 pF	150	350	550				
Propagation delay time (L→H)	t _{pLH}				C _L =10 pF		100	_			
Switching Time Dispersion between ON and OFF	t _{pHL} -t _{pLH}	5	$R_L = 20 \text{ k}\Omega$ (Note 1)	C _L = 100 pF)_	400	ns				
Propagation Delay Skew (Note 2)	t _{pLH} -t _{pHL}				-50	_	450				
Common mode transient immunity at high output level	СМн	6	$V_{CM} = 1500 V_{p-p},$ $R_L = 20 k\Omega, Ta = 2$	I _F = 0 mA 5 °C	15	_	_	kV/μs			
Common mode transient Immunity at low output level	CML	6	V_{CM} = 1500 V_{p-p} , R_L = 20 $k\Omega$, Ta = 2	IF = 10 mA 5 °C	-15	AF.		kV/μs			

^{*}All typical values are at Ta = 25 °C

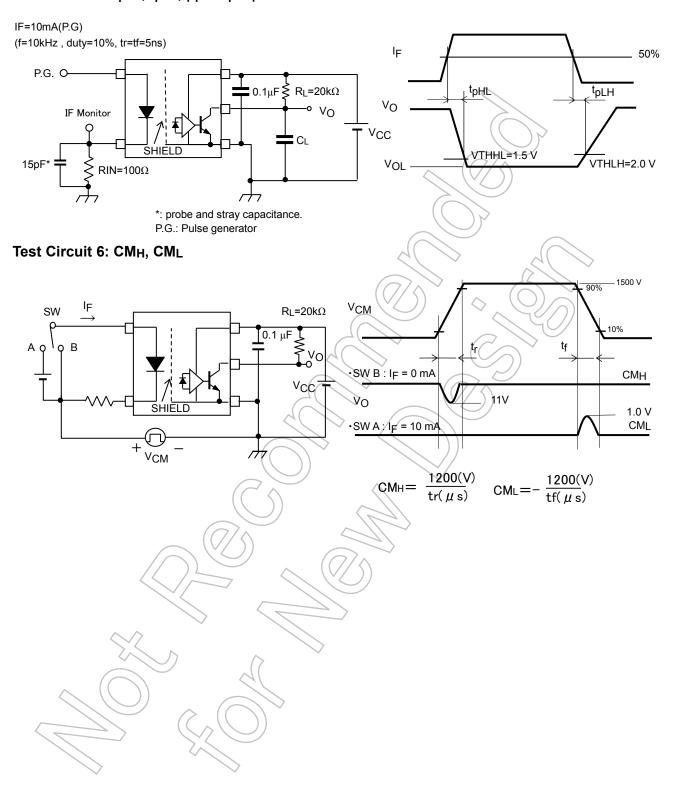
Note: A ceramic capacitor (0.1 μF) should be connected from pin 6 (V_{CC}) to pin 4 (GND) to stabilize the operation of the high gain linear amplifier. Failure to provide the bypass may impair the switching property. The total lead length between capacitor and coupler should not exceed 1 cm.

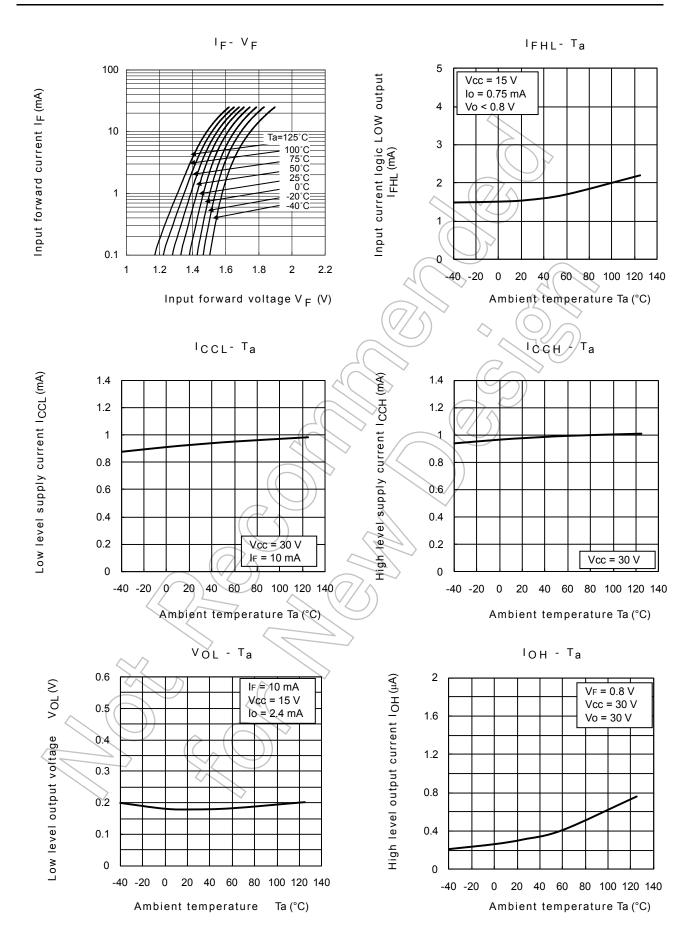
Note 1: f = 10kHz, duty=10%, input current tr = tf = 5 ns

Note 2: Propagation delay skew is defined as the propagation delay time of the largest or smallest tpLH minus the largest or smallest tpHL of multiple samples. Evaluations of these samples are conducted under identical test conditions (supply voltage, input current, temperature, etc.).

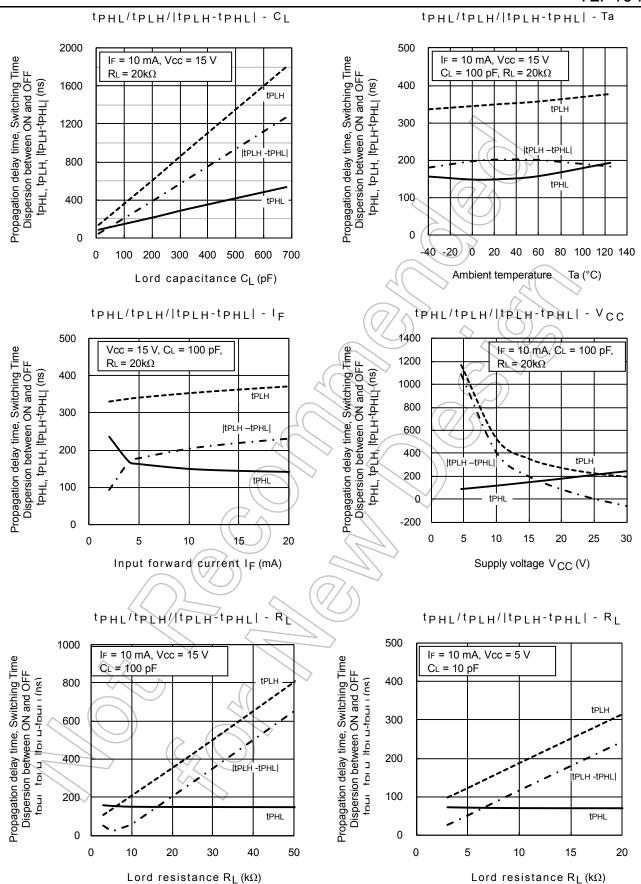


Test Circuit 5: tpHL, tpLH, |tpHL-tpLH|





NOTE: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



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PRECAUTIONS OF SURFACE MOUNTING TYPE PHOTOCOUPLER SOLDERING & GENERAL STORAGE

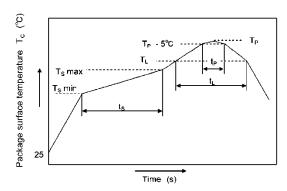
Precautions for Soldering

The soldering temperature should be controlled as closely as possible to the conditions shown below, irrespective of whether a soldering iron or a reflow soldering method is used.

1) When Using Soldering Reflow

The soldering temperature profile is based on the package surface temperature (See the figure shown below.)

An example of a temperature profile when lead (Pb)-free solder is used



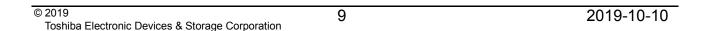
	Symbol	Min	Max	Unit
Preheat temperature	Ts	150	200	°C
Preheat time	ts	60	120	s
Ramp-up rate (T_L to T_P)) \	3	°C/s
Liquidus temperature	Ţ) 2	17	°Ç
Time above T _L	t _b	60	150	S
Peak temperature	T _P	/	260	7 /c
Time during which T_c is between ($T_P - 5$) and T_P	£		30	5
Ramp-down rate (T _P to T _L))	\Diamond	6)°C/s
			\wedge	(//)

- Reflow soldering must be performed once or twice.
- The mounting should be completed with the interval from the first to the last mountings being 2 weeks.
- 2) When using soldering Flow
 - Apply preheating of 150 °C for 60 to 120 seconds.
 - Mounting condition of 260 °C or less within 10 seconds is recommended.
 - Flow soldering must be performed once
- 3) When using soldering Iron
 - Complete soldering within 10 seconds for lead temperature not exceeding 260 °C or within 3 seconds not exceeding 350 °C.
 - Heating by soldering iron must be only once per 1 lead.



(2) Precautions for General Storage

- 1) Do not store devices at any place where they will be exposed to moisture or direct sunlight.
- 2) When transportation or storage of devices, follow the cautions indicated on the carton box.
- 3) The storage area temperature should be kept within a temperature range of 5 °C to 35 °C, and relative humidity should be maintained at between 45% and 75%.
- 4) Do not store devices in the presence of harmful (especially corrosive) gases, or in dusty conditions.
- 5) Use storage areas where there is minimal temperature fluctuation. Because rapid temperature changes can cause condensation to occur on stored devices, resulting in lead oxidation or corrosion, as a result, the solderability of the leads will be degraded.
- 6) When repacking devices, use anti-static containers.
- 7) Do not apply any external force or load directly to devices while they are in storage.
- 8) If devices have been stored for more than two years, even though the above conditions have been followed, it is recommended that solderability of them should be tested before they are used.



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